## Notice of References Cited Application/Control No. 10/587,612 Examiner Shih-wen hsieh Applicant(s)/Patent Under Reexamination TAMAI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,075,069	06-2000	Takemoto, Kiyohiko	523/160
	В	US-			
	C	US-		·	
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
,	1	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.